

Notice of References Cited		Application/Control No. 09/872,647	Applicant(s)/Patent Under Reexamination SRIVASTAVA ET AL.	
		Examiner Satish S. Rampuria	Art Unit 2191	Page 1 of 1

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Correction

Notice of References Cited		Application/Control No. 09/872,647	Applicant(s)/Patent Under Reexamination SRIVASTAVA ET AL.	
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X	Palnitkar et al., Finite state machine trace analysis program, 1994, IEEE, pg. 52-57	

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